Product data sheet

1. General description

Planar passivated SCR with faster switching performance and sensitive gate in a SOT223 surface mounted plastic package. This SCR with enhanced commutation performance is also designed to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- · Fast commutation performance for higher frequency operation
- Full wave rectified AC applications
- Sensitive gate
- · Direct triggering from microcontrollers, low power drivers and logic ICs

3. Applications

- Earth leakage circuit breakers (ELCB/GFI)
- · Ignition circuits (gas appliances, small engines and HID lighting)

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	meter Conditions Values				Unit			
Absolute maximum rating									
V_{RRM}	repetitive peak reverse voltage			600			V		
I _{T(AV)}	average on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 1</u>		0.63			А		
I _{T(RMS)}	RMS on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 2</u> ; <u>Fig. 3</u>	1			Α			
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5	8		А				
		half sine wave; $T_{J(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	9		А				
T _j	junction temperature		125		°C				
Symbol	Parameter	Conditions	Min Typ Max		Unit				
Static ch	aracteristics								
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 \text{ °C}; Fig. 9$		70	200	450	μA		
Dynamic	characteristics								
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; R_{GK} = 1 k Ω ; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 14	350 800 -		V/µs				
		V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14		-	25	-	V/µs		

SCR

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		A - □ K
2	А	anode		G G
3	G	gate		sym037
4	mb	mb; connected to anode	1 2 3	

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BT168GWF	SOT223	BT168GWF, 115	Reel	1000	SOT223	03-Jun-2016

7. Marking

Table 4. Marking codes

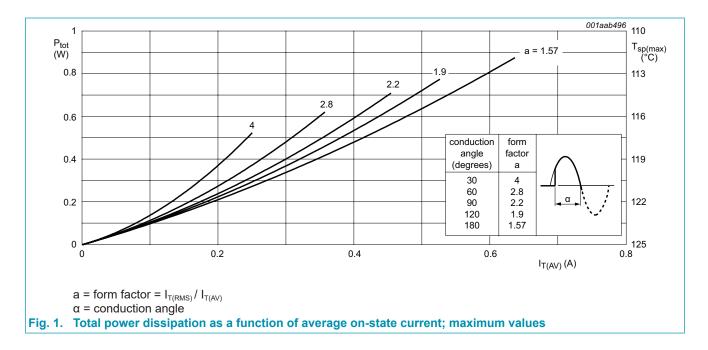
Type number	er Marking codes					
	Assembly factory: d	Assembly factory: L				
BT168GWF	Jdxxx 168GWF	JLxxx 168GWF				

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V_{DRM}	repetitive peak off-state voltage		600	V
V_{RRM}	repetitive peak reverse voltage		600	V
I _{T(AV)}	average on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 1</u>	0.63	А
I _{T(RMS)}	RMS on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 2</u> ; <u>Fig. 3</u>	1	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5	8	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	9	А
l ² t	I ² t for fusing	t _P = 10 ms; SIN	0.32	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 400 mA	50	A/µs
I _{GM}	peak gate current		1	А
V_{RGM}	peak reverse gate voltage		5	V
P_{GM}	peak gate power		2	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.1	W
T _{stg}	storage temperature		-40 to 150	°C
T _j	junction temperature		125	°C



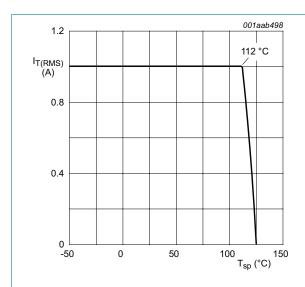
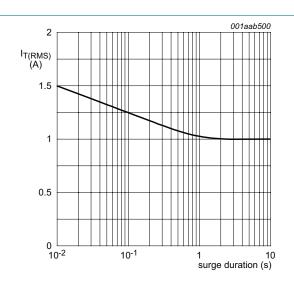
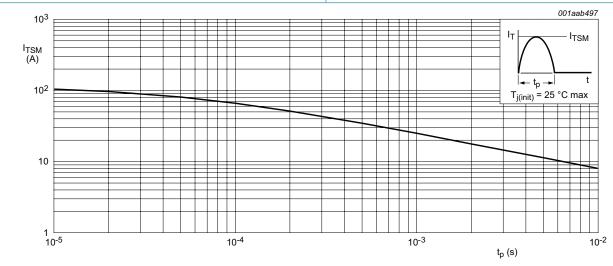


Fig. 2. RMS on-state current as a function of solder point temperature; maximum values



f = 50 Hz; T_{sp} = 112 °C Fig. 3. RMS on-state current as a function of surge duration for sinusoidal currents



 $t_p \le 10$ ms Fig. 4. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

SCF

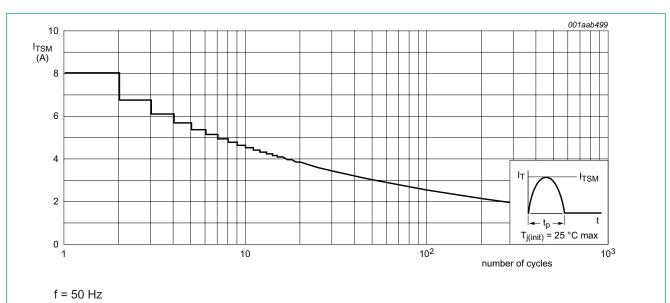
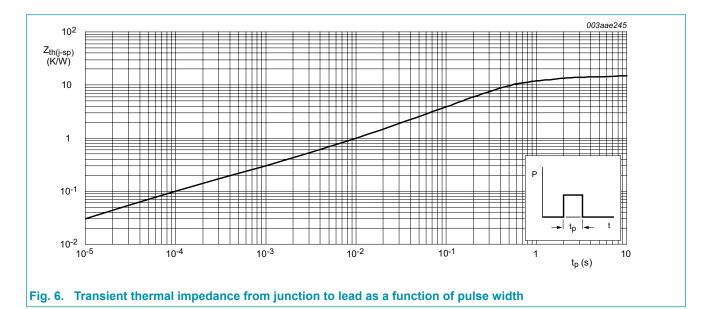


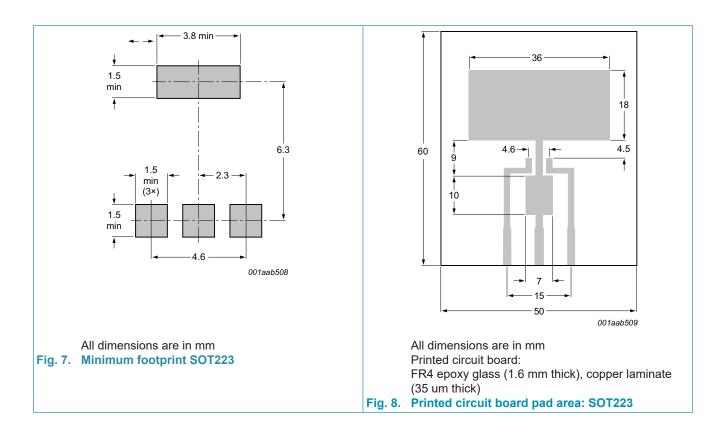
Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal currents cycles; maximum values

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-sp)}}$	thermal resistance from junction to solder point	<u>Fig. 6</u>	-	-	15	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	printed circuit board mounted: minimum footprint; <u>Fig. 7</u>	-	156	-	K/W
		printed circuit board mounted: pad area; Fig. 8	-	70	-	K/W





10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 \text{ °C};$ Fig. 9	70	200	450	μA
I _L	latching current	$V_D = 12 \text{ V}; I_G = 0.5 \text{ mA}; T_j = 25 \text{ °C};$ $R_{GK(ext)} = 1 \text{ k}\Omega; Fig. 10$	3	7.5	13	mA
I _H	holding current	V_D = 12 V; T_j = 25 °C; $R_{GK(ext)}$ = 1 kΩ; Fig. 11	0.5	4.1	10	mA
V _T	on-state voltage	I _T = 1.2 A; T _j = 25 °C; <u>Fig. 12</u>	-	1.35	1.7	V
V _{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 \text{ °C};$ Fig. 13	-	0.5	0.8	V
		V _D = 600 V; I _T = 10 mA; T _j = 125 °C	0.2	0.3	-	V
I _D	off-state current	$V_D = 600 \text{ V}; R_{GK(ext)} = 1 \text{ k}\Omega; T_j = 125 \text{ °C}$	-	0.05	0.1	mA
I _R	reverse current	$V_R = 600 \text{ V}; R_{GK(ext)} = 1 \text{ k}\Omega; T_j = 125 \text{ °C}$	-	0.05	0.1	mA
Dynamic	characteristics				'	
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; R_{GK} =1kΩ; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 14	350	800	-	V/µs
		V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 14	-	25	-	V/µs

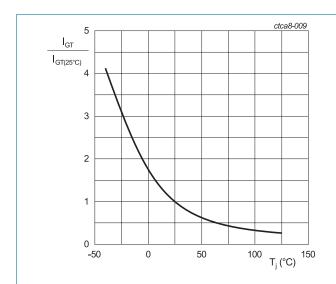


Fig. 9. Normalized gate trigger current as a function of junction temperature

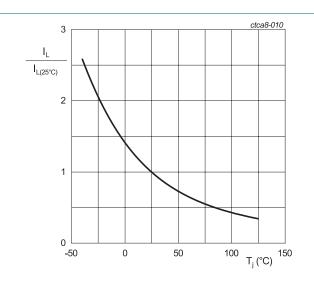


Fig. 10. Normalized latching current as a function of junction temperature

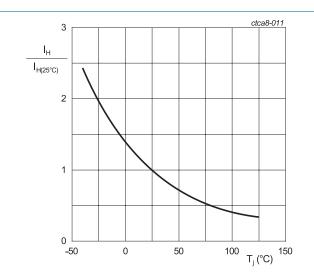
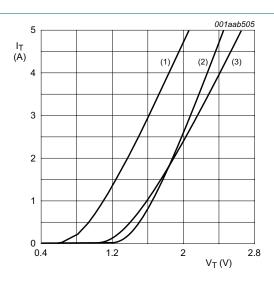


Fig. 11. Normalized holding current as a function of junction temperature



 $V_o = 1.0 \text{ V}; R_s = 0.27 \Omega$

(1) T_i = 125 °C; typical values

(2) T_j = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

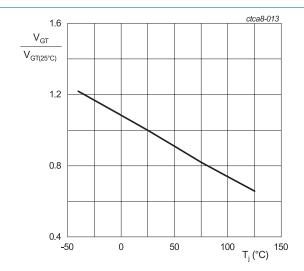
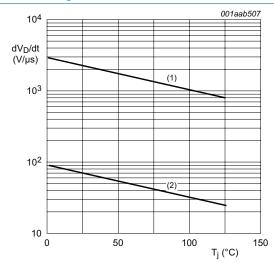


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

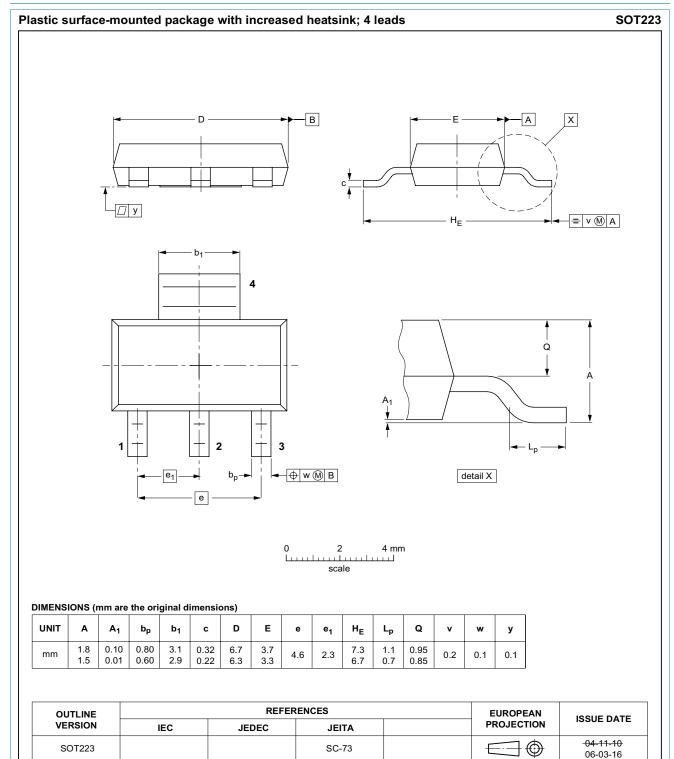


(1) $R_{GK} = 1 kΩ$;

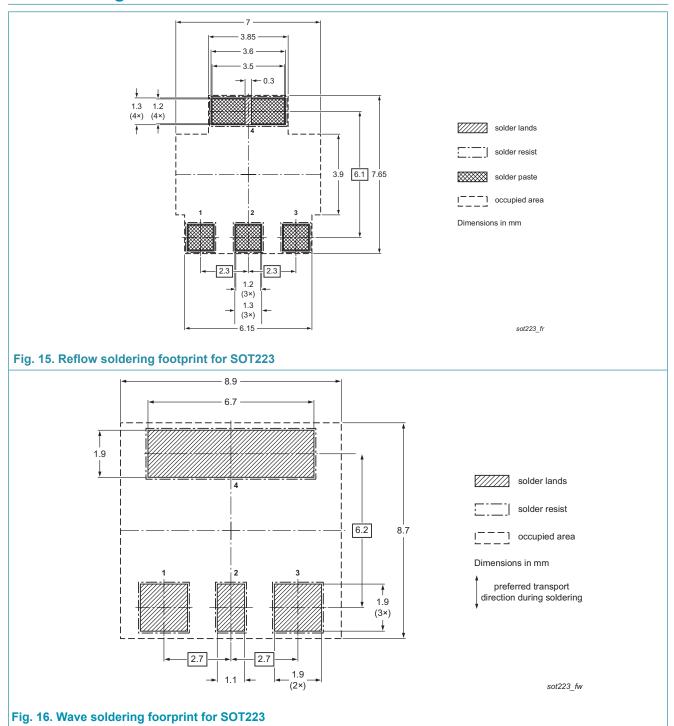
(2) gate open circuit

Fig. 14. Critical rate of rise of off-state voltage as a function of junction temperature; typical values

11. Package outline



12. Soldering



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 28 February 2025

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